



Static & Dynamic Module Tester



- Static test
- Heating up
- Dynamic test at $\leq 180^{\circ}\text{C}$
- Cooling down
- Second static test

Static & Dynamic Module Tester

The module tester from MicroContact covers the complete high current test. After the first static test, the modules are heated to the required test temperature in a short time and tested dynamically. After a short active cooling phase, the modules are statically tested a second time and the test results are compared.

System description:

- Static test
- Heating up to $\leq 180^{\circ}\text{C}$
- Dynamic test from top under temperature
- Cooling down to $< 30^{\circ}\text{C}$
- Second static test
- System cycle time ≥ 28 seconds
- Module dimension up to 230mm x 130mm x 40mm

Test definitions for VX Instruments:

Static test:

- Up to 3'000V, 3'000A
- Pulse $> 100\mu\text{s}$
- Wide Bandgap testing (Si, SiC, GaN)
- MOSFET's, IGBT's
- RDS(ON)
- VBRSS, IDSS, IGSS
- VGSTH
- VSD
- ...

Dynamic test:

- Up to 1'500V, 10'000A, pulse $> 0.5\mu\text{s}$
- Multipulse test
- Short circuit test
- UIS (unclamped inductive switching)
- CIS (clamped inductive switching)